

**Search Notes**

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Examiner

Le Nguyen

Applicant(s)/Patent under  
Reexamination

BURRELL, BRANDON

Art Unit

2174

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
US-PG Pub, USPAT: 715/513,529760; 713/1,2,100; 700/17	7/9/2007	LVN